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Details

Product Status	Discontinued at Digi-Key
Module/Board Type	MCU, FPGA
Core Processor	ARM Cortex-A9
Co-Processor	Zynq-7000 (Z-7010)
Speed	12MHz
Flash Size	16MB
RAM Size	512MB
Connector Type	Arduino
Size / Dimension	-
Operating Temperature	0°C ~ 70°C
Purchase URL	https://www.e-xfl.com/product-detail/trenz-electronic/te0723-02m

Table 1: Absolute Maximum Ratings⁽¹⁾ (Cont'd)

Symbol	Description	Min	Max	Units
V_{IN} ⁽³⁾⁽⁴⁾⁽⁵⁾	I/O input voltage for HR I/O banks	−0.40	$V_{CCO} + 0.55$	V
	I/O input voltage (when $V_{CCO} = 3.3V$) for V_{REF} and differential I/O standards except TMDS_33 ⁽⁶⁾	−0.40	2.625	V
V_{CCBATT}	Key memory battery backup supply	−0.5	2.0	V
GTP Transceiver (XC7Z015 Only)				
$V_{MGTAVCC}$	Analog supply voltage for the GTP transmitter and receiver circuits	−0.5	1.1	V
$V_{MGTAVTT}$	Analog supply voltage for the GTP transmitter and receiver termination circuits	−0.5	1.32	V
$V_{MGTREFCLK}$	Reference clock absolute input voltage	−0.5	1.32	V
V_{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	−0.5	1.26	V
$I_{DCIN-FLOAT}$	DC input current for receiver input pins DC coupled RX termination = floating	—	14	mA
$I_{DCIN-MGTAVTT}$	DC input current for receiver input pins DC coupled RX termination = $V_{MGTAVTT}$	—	12	mA
$I_{DCIN-GND}$	DC input current for receiver input pins DC coupled RX termination = GND	—	6.5	mA
$I_{DCOUT-FLOAT}$	DC output current for transmitter pins DC coupled RX termination = floating	—	14	mA
$I_{DCOUT-MGTAVTT}$	DC output current for transmitter pins DC coupled RX termination = $V_{MGTAVTT}$	—	12	mA
XADC				
V_{CCADC}	XADC supply relative to GNDADC	−0.5	2.0	V
V_{REFP}	XADC reference input relative to GNDADC	−0.5	2.0	V
Temperature				
T_{STG}	Storage temperature (ambient)	−65	150	°C
T_{SOL}	Maximum soldering temperature for Pb/Sn component bodies ⁽⁷⁾	—	+220	°C
	Maximum soldering temperature for Pb-free component bodies ⁽⁷⁾	—	+260	°C
T_j	Maximum junction temperature ⁽⁷⁾	—	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- Applies to both MIO supply banks V_{CCO_MIO0} and V_{CCO_MIO1} .
- The lower absolute voltage specification always applies.
- For I/O operation, refer to the *7 Series FPGAs SelectIO Resources User Guide* ([UG471](#)) or the *Zynq-7000 All Programmable SoC Technical Reference Manual* ([UG585](#)).
- The maximum limit applies to DC signals. For maximum undershoot and overshoot AC specifications, see [Table 4](#).
- See [Table 11](#) for TMDS_33 specifications.
- For soldering guidelines and thermal considerations, see the *Zynq-7000 All Programmable SoC Packaging and Pinout Specification* ([UG865](#)).

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾

Symbol	Description	Min	Typ	Max	Units
PS					
V_{CCPINT}	PS internal logic supply voltage	0.95	1.00	1.05	V
V_{CCPAUX}	PS auxiliary supply voltage	1.71	1.80	1.89	V
V_{CCPLL}	PS PLL supply	1.71	1.80	1.89	V
V_{CCO_DDR}	PS DDR I/O supply voltage	1.14	—	1.89	V
V_{CCO_MIO} ⁽³⁾	PS MIO I/O supply voltage for MIO banks	1.71	—	3.465	V

Table 4: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for PS I/O and PL HR I/O Banks⁽¹⁾⁽²⁾

AC Voltage Overshoot	% of UI @-40°C to 125°C	AC Voltage Undershoot	% of UI @-40°C to 125°C
$V_{CCO} + 0.55$	100	-0.40	100
		-0.45	61.7
		-0.50	25.8
		-0.55	11.0
$V_{CCO} + 0.60$	46.6	-0.60	4.77
$V_{CCO} + 0.65$	21.2	-0.65	2.10
$V_{CCO} + 0.70$	9.75	-0.70	0.94
$V_{CCO} + 0.75$	4.55	-0.75	0.43
$V_{CCO} + 0.80$	2.15	-0.80	0.20
$V_{CCO} + 0.85$	1.02	-0.85	0.09
$V_{CCO} + 0.90$	0.49	-0.90	0.04
$V_{CCO} + 0.95$	0.24	-0.95	0.02

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. The peak voltage of the overshoot or undershoot, and the duration above $V_{CCO} + 0.20V$ or below GND $-0.20V$, must not exceed the values in this table.

Table 5: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1LI	
$I_{CCPINTQ}$	PS quiescent V_{CCPINT} supply current	XC7Z007S	N/A	122	122	N/A	mA
		XC7Z012S	N/A	122	122	N/A	mA
		XC7Z014S	N/A	122	122	N/A	mA
		XC7Z010	122	122	122	85	mA
		XC7Z015	122	122	122	85	mA
		XC7Z020	122	122	122	85	mA
		XA7Z010	N/A	N/A	122	N/A	mA
		XA7Z020	N/A	N/A	122	N/A	mA
		XQ7Z020	N/A	122	122	85	mA
$I_{CCPAUXQ}$	PS quiescent V_{CCPAUX} supply current	XC7Z007S	N/A	13	13	N/A	mA
		XC7Z012S	N/A	13	13	N/A	mA
		XC7Z014S	N/A	13	13	N/A	mA
		XC7Z010	13	13	13	11	mA
		XC7Z015	13	13	13	11	mA
		XC7Z020	13	13	13	11	mA
		XA7Z010	N/A	N/A	13	N/A	mA
		XA7Z020	N/A	N/A	13	N/A	mA
		XQ7Z020	N/A	13	13	11	mA

Table 15: Zynq-7000 Device Speed Grade Designations (Cont'd)

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC7Z020			-3E, -2E, -2I, -1C, -1I, -1LI
XA7Z010			-1I, -1Q
XA7Z020			-1I, -1Q
XQ7Z020			-2I, -1I, -1Q, -1LI

Production Silicon and Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

Table 16 lists the production released Zynq-7000 device, speed grade, and the minimum corresponding supported speed specification version and software revisions. The software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 16: Zynq-7000 Device Production Software and Speed Specification Release

Device	Speed Grade Designations						
	-3E	-2E	-2I	-1C	-1I	-1LI	-1Q
XC7Z007S	N/A	Vivado tools 2016.3 v1.11				N/A	N/A
XC7Z012S	N/A	Vivado tools 2016.3 v1.11				N/A	N/A
XC7Z014S	N/A	Vivado tools 2016.3 v1.11				N/A	N/A
XC7Z010	ISE tools 14.5 v1.06 and Vivado tools 2013.1 v1.06	ISE tools 14.4 and the 14.4 device pack v1.05 and Vivado tools 2013.1 v1.06				Vivado tools 2014.4 v1.11	N/A
XC7Z015	Vivado tools 2013.4 v1.09					Vivado tools 2014.4 v1.11	N/A
XC7Z020	ISE tools 14.5 v1.06 and Vivado tools 2013.1 v1.06	ISE tools 14.4 and the 14.4 device pack v1.05 and Vivado tools 2013.1 v1.06				Vivado tools 2014.4 v1.11	N/A
XA7Z010	N/A				ISE tools 14.5 v1.04 and Vivado tools 2013.1 v1.04	N/A	ISE tools 14.6 v1.05 and Vivado tools 2013.2 v1.05
XA7Z020	N/A				ISE tools 14.5 v1.04 and Vivado tools 2013.1 v1.04	N/A	ISE tools 14.6 v1.05 and Vivado tools 2013.2 v1.05
XQ7Z020	N/A		ISE tools 14.6 v1.05 and Vivado tools 2013.2 v1.05	N/A	ISE tools 14.6 v1.05 and Vivado tools 2013.2 v1.05	Vivado tools 2015.4 v1.10	ISE tools 14.7 v1.06 and Vivado tools 2013.3 v1.06

Selecting the Correct Speed Grade and Voltage in the Vivado Tools

It is important to select the correct device speed grade and voltage in the Vivado tools for the device that you are selecting.

To select the -3, -2, or -1 (PL 1.0V) speed specifications in the Vivado tools, select the **Zynq-7000**, **XA Zynq-7000**, or **Defense Grade Zynq-7000** sub-family, and then select the part name that is the device name followed by the package name followed by the speed grade. For example, select the **xc7z020clg484-3** part name for the XC7Z020 device in the CLG484 package and -3 speed grade.

To select the -1LI (PL 0.95V) speed specifications in the Vivado tools, select the **Zynq-7000** sub-family and then select the part name that is the device name followed by an *i* followed by the package name followed by the speed grade. For example, select the **xc7z020iclg484-1L** part name for the XC7Z020 device in the CLG484 package and -1LI (PL 0.95V) speed grade. The -1LI (PL 0.95V) speed specifications are not supported in the ISE tools.

A similar part naming convention applies to the speed specifications selection in the ISE tools for supported devices. See [Table 16](#) for the subset of the Zynq-7000 devices supported in the ISE tools.

PS Performance Characteristics

For further design requirement details, refer to the *Zynq-7000 All Programmable SoC Technical Reference Manual* ([UG585](#)).

Table 17: CPU Clock Domains Performance

Symbol	Clock Ratio	Description	Speed Grade				Units
			-3	-2	-1C/-1I/-1LI	-1Q	
F _{CPU_6X4X_621_MAX} ⁽¹⁾	6:2:1	Maximum CPU clock frequency	866	766	667	667	MHz
F _{CPU_3X2X_621_MAX}		Maximum CPU_3X clock frequency	433	383	333	333	MHz
F _{CPU_2X_621_MAX}		Maximum CPU_2X clock frequency	288	255	222	222	MHz
F _{CPU_1X_621_MAX}		Maximum CPU_1X clock frequency	144	127	111	111	MHz
F _{CPU_6X4X_421_MAX} ⁽¹⁾	4:2:1	Maximum CPU clock frequency	710	600	533	533	MHz
F _{CPU_3X2X_421_MAX}		Maximum CPU_3X clock frequency	355	300	267	267	MHz
F _{CPU_2X_421_MAX}		Maximum CPU_2X clock frequency	355	300	267	267	MHz
F _{CPU_1X_421_MAX}		Maximum CPU_1X clock frequency	178	150	133	133	MHz

Notes:

1. The maximum frequency during BootROM execution is 500 MHz across all speed specifications.

Table 18: PS DDR Clock Domains Performance⁽¹⁾

Symbol	Description	Speed Grade				Units
		-3	-2	-1C/-1I/-1LI	-1Q	
F _{DDR3_MAX}	Maximum DDR3 interface performance	1066	1066	1066	1066	Mb/s
F _{DDR3L_MAX}	Maximum DDR3L interface performance	1066	1066	1066	1066	Mb/s
F _{DDR2_MAX}	Maximum DDR2 interface performance	800	800	800	800	Mb/s
F _{LPDDR2_MAX}	Maximum LPDDR2 interface performance	800	800	800	800	Mb/s
F _{DDRCLK_2XMAX}	Maximum DDR_2X clock frequency	444	408	355	355	MHz

Notes:

1. All performance numbers apply to both internal and external V_{REF} configurations.

Table 19: PS-PL Interface Performance

Symbol	Description	Min	Max	Units
F _{EMIOGEMCLK}	EMIO gigabit Ethernet controller maximum frequency	–	125	MHz
F _{EMIOSDCLK}	EMIO SD controller maximum frequency	–	25	MHz
F _{EMIOSPICLK}	EMIO SPI controller maximum frequency	–	25	MHz
F _{EMIOJTAGCLK}	EMIO JTAG controller maximum frequency	–	20	MHz
F _{EMIOTRACECLK}	EMIO trace controller maximum frequency	–	125	MHz
F _{FTMCLK}	Fabric trace monitor maximum frequency	–	125	MHz
F _{EMIODMACLK}	DMA maximum frequency	–	100	MHz
F _{AXI_MAX}	Maximum AXI interface performance	–	250	MHz

Table 23: PS Reset/Power Supply Timing Requirements

Symbol	Description	PS_CLK Frequency (MHz)	Min	Max	Units
$T_{SLW}^{(1)}$	128 KB CRC eFUSE disabled and PLL enabled. Default configuration	30	12	39	ms
		33.33	12	40	ms
		60	13	40	ms
	128 KB CRC eFUSE disabled and PLL in bypass.	30	–32	13	ms
		33.33	–27	13	ms
		60	–9	25	ms
	128 KB CRC eFUSE enabled and PLL enabled. ⁽²⁾	30	–19	9	ms
		33.33	–16	12	ms
		60	–3	25	ms
	128 KB CRC eFUSE enabled and PLL in bypass. ⁽²⁾	30	–830	–788	ms
		33.33	–746	–705	ms
		60	–408	–374	ms

Notes:

- Valid for power supply ramp times of less than 6 ms. For ramp times longer than 6 ms, see the BootROM Performance section of the *Zynq-7000 All Programmable SoC Technical Reference Manual* (UG585).
- If any PS and PL power supplies are tied together, observe the PS_POR_B assertion time requirement (T_{PSPOR}) in Table 22 and its accompanying note.

PS Configuration

Table 24: Processor Configuration Access Port Switching Characteristics

Symbol	Description	Min	Typ	Max	Units
F_{PCAPCK}	Maximum processor configuration access port (PCAP) frequency	–	–	100	MHz

DDR Memory Interfaces

Table 25: DDR3 Interface Switching Characteristics (1066 Mb/s)⁽¹⁾

Symbol	Description	Min	Max	Units
$T_{DQVALID}^{(2)}$	Input data valid window	450	–	ps
$T_{DQDS}^{(3)}$	Output DQ to DQS skew	131	–	ps
$T_{DQDH}^{(4)}$	Output DQS to DQ skew	288	–	ps
T_{DQSS}	Output clock to DQS skew	–0.11	0.09	T_{CK}
$T_{CACK}^{(5)}$	Command/address output setup time with respect to CLK	532	–	ps
$T_{CKCA}^{(6)}$	Command/address output hold time with respect to CLK	637	–	ps

Notes:

- Recommended $V_{CCO_DDR} = 1.5V \pm 5\%$.
- Measurement is taken from V_{REF} to V_{REF} .
- Measurement is taken from either the rising edge of DQ that crosses $V_{IH}(AC)$ or the falling edge of DQ that crosses $V_{IL}(AC)$ to V_{REF} of DQS.
- Measurement is taken from either the rising edge of DQ that crosses $V_{IL}(DC)$ or the falling edge of DQ that crosses $V_{IH}(DC)$ to V_{REF} of DQS.
- Measurement is taken from either the rising edge of CMD/ADDR that crosses $V_{IH}(AC)$ or the falling edge of CMD/ADDR that crosses $V_{IL}(AC)$ to V_{REF} of CLK.
- Measurement is taken from either the rising edge of CMD/ADDR that crosses $V_{IL}(DC)$ or the falling edge of CMD/ADDR that crosses $V_{IH}(DC)$ to V_{REF} of CLK.

Table 28: DDR3L Interface Switching Characteristics (800 Mb/s)⁽¹⁾ (Cont'd)

Symbol	Description	Min	Max	Units
T _{CKCA} ⁽⁶⁾	Command/address output hold time with respect to CLK	853	–	ps

Notes:

1. Recommended $V_{CCO_DDR} = 1.35V \pm 5\%$.
2. Measurement is taken from V_{REF} to V_{REF} .
3. Measurement is taken from either the rising edge of DQ that crosses $V_{IH}(AC)$ or the falling edge of DQ that crosses $V_{IL}(AC)$ to V_{REF} of DQS.
4. Measurement is taken from either the rising edge of DQ that crosses $V_{IL}(DC)$ or the falling edge of DQ that crosses $V_{IH}(DC)$ to V_{REF} of DQS.
5. Measurement is taken from either the rising edge of CMD/ADDR that crosses $V_{IH}(AC)$ or the falling edge of CMD/ADDR that crosses $V_{IL}(AC)$ to V_{REF} of CLK.
6. Measurement is taken from either the rising edge of CMD/ADDR that crosses $V_{IL}(DC)$ or the falling edge of CMD/ADDR that crosses $V_{IH}(DC)$ to V_{REF} of CLK.

Table 29: LPDDR2 Interface Switching Characteristics (800 Mb/s)⁽¹⁾

Symbol	Description	Min	Max	Units
T _{DQVALID} ⁽²⁾	Input data valid window	500	–	ps
T _{DQDS} ⁽³⁾	Output DQ to DQS skew	196	–	ps
T _{DQDH} ⁽⁴⁾	Output DQS to DQ skew	328	–	ps
T _{DQSS}	Output clock to DQS skew	0.90	1.06	T _{CK}
T _{CACK} ⁽⁵⁾	Command/address output setup time with respect to CLK	202	–	ps
T _{CKCA} ⁽⁶⁾	Command/address output hold time with respect to CLK	353	–	ps

Notes:

1. Recommended $V_{CCO_DDR} = 1.2V \pm 5\%$.
2. Measurement is taken from V_{REF} to V_{REF} .
3. Measurement is taken from either the rising edge of DQ that crosses $V_{IH}(AC)$ or the falling edge of DQ that crosses $V_{IL}(AC)$ to V_{REF} of DQS.
4. Measurement is taken from either the rising edge of DQ that crosses $V_{IL}(DC)$ or the falling edge of DQ that crosses $V_{IH}(DC)$ to V_{REF} of DQS.
5. Measurement is taken from either the rising edge of CMD/ADDR that crosses $V_{IH}(AC)$ or the falling edge of CMD/ADDR that crosses $V_{IL}(AC)$ to V_{REF} of CLK.
6. Measurement is taken from either the rising edge of CMD/ADDR that crosses $V_{IL}(DC)$ or the falling edge of CMD/ADDR that crosses $V_{IH}(DC)$ to V_{REF} of CLK.

Table 30: LPDDR2 Interface Switching Characteristics (400 Mb/s)⁽¹⁾

Symbol	Description	Min	Max	Units
T _{DQVALID} ⁽²⁾	Input data valid window	500	–	ps
T _{DQDS} ⁽³⁾	Output DQ to DQS skew	664	–	ps
T _{DQDH} ⁽⁴⁾	Output DQS to DQ skew	766	–	ps
T _{DQSS}	Output clock to DQS skew	0.90	1.06	T _{CK}
T _{CACK} ⁽⁵⁾	Command/address output setup time with respect to CLK	731	–	ps
T _{CKCA} ⁽⁶⁾	Command/address output hold time with respect to CLK	907	–	ps

Notes:

1. Recommended $V_{CCO_DDR} = 1.2V \pm 5\%$.
2. Measurement is taken from V_{REF} to V_{REF} .
3. Measurement is taken from either the rising edge of DQ that crosses $V_{IH}(AC)$ or the falling edge of DQ that crosses $V_{IL}(AC)$ to V_{REF} of DQS.
4. Measurement is taken from either the rising edge of DQ that crosses $V_{IL}(DC)$ or the falling edge of DQ that crosses $V_{IH}(DC)$ to V_{REF} of DQS.
5. Measurement is taken from either the rising edge of CMD/ADDR that crosses $V_{IH}(AC)$ or the falling edge of CMD/ADDR that crosses $V_{IL}(AC)$ to V_{REF} of CLK.
6. Measurement is taken from either the rising edge of CMD/ADDR that crosses $V_{IL}(DC)$ or the falling edge of CMD/ADDR that crosses $V_{IH}(DC)$ to V_{REF} of CLK.

Static Memory Controller

Table 33: SMC Interface Delay Characteristics⁽¹⁾⁽²⁾

Symbol	Description	Min	Max	Units
T _{NANDDOUT}	NAND_IO output delay from last register to pad	4.12	6.45	ns
T _{NANDALE}	NAND_ALE output delay from last register to pad	5.08	6.33	ns
T _{NANDCLE}	NAND_CLE output delay from last register to pad	4.87	6.40	ns
T _{NANDWE}	NAND_WE_B output delay from last register to pad	4.69	5.89	ns
T _{NANDRE}	NAND_RE_B output delay from last register to pad	5.12	6.44	ns
T _{NANDCE}	NAND_CE_B output delay from last register to pad	4.68	5.89	ns
T _{NANDDIN}	NAND_IO setup time and input delay from pad to first register	1.48	3.09	ns
T _{NANDBUSY}	NAND_BUSY setup time and input delay from pad to first register	2.48	3.33	ns
T _{SRAMA}	SRAM_A output delay from last register to pad	3.94	5.73	ns
T _{SRAMDOUT}	SRAM_DQ output delay from last register to pad	4.66	6.45	ns
T _{SRAMCE}	SRAM_CE output delay from last register to pad	4.57	5.95	ns
T _{SRAMOE}	SRAM_OE_B output delay from last register to pad	4.79	6.13	ns
T _{SRAMBLS}	SRAM_BLS_B output delay from last register to pad	5.25	6.74	ns
T _{SRAMWE}	SRAM_WE_B output delay from last register to pad	5.12	6.48	ns
T _{SRAMDIN}	SRAM_DQ setup time and input delay from pad to first register	1.93	3.05	ns
T _{SRAMWAIT}	SRAM_WAIT setup time and input delay from pad to first register	2.26	3.15	ns
F _{SMC_REF_CLK}	SMC reference clock frequency	–	100	MHz

Notes:

1. All parameters do not include the package flight time and register controlled delays.
2. Refer to the ARM® PrimeCell® Static Memory Controller (PL350 series) Technical Reference Manual for more SMC timing details.

Quad-SPI Interfaces

Table 34: Quad-SPI Interface Switching Characteristics

Symbol	Description	Load Conditions	Min	Max	Units
Feedback Clock Enabled					
T _{DCQSPICLK1}	Quad-SPI clock duty cycle	All ⁽¹⁾⁽²⁾	44	56	%
T _{QSPICKO1}	Data and slave select output delay	15 pF ⁽¹⁾	−0.10 ⁽³⁾	2.30	ns
		30 pF ⁽²⁾	−1.00	3.80	
T _{QSPIDCK1}	Input data setup time	15 pF ⁽¹⁾	2.00	−	ns
		30 pF ⁽²⁾	3.30	−	
T _{QSPICKD1}	Input data hold time	15 pF ⁽¹⁾	1.30	−	ns
		30 pF ⁽²⁾	1.50	−	
T _{QSPISSCLK1}	Slave select asserted to next clock edge	All ⁽¹⁾⁽²⁾	1	−	F _{QSPI_REF_CLK} cycle
T _{QSPICLKSS1}	Clock edge to slave select deasserted	All ⁽¹⁾⁽²⁾	1	−	F _{QSPI_REF_CLK} cycle
F _{QSPICLK1}	Quad-SPI device clock frequency	15 pF ⁽¹⁾	−	100 ⁽⁴⁾	MHz
		30 pF ⁽²⁾	−	70 ⁽⁴⁾	
Feedback Clock Disabled					
T _{DCQSPICLK2}	Quad-SPI clock duty cycle	All ⁽¹⁾⁽²⁾	44	56	%
T _{QSPICKO2}	Data and slave select output delay	15 pF ⁽¹⁾	−0.10	3.80	ns
		30 pF ⁽²⁾	−1.00	3.80	ns
T _{QSPIDCK2}	Input data setup time	All ⁽¹⁾⁽²⁾	6	−	ns
T _{QSPICKD2}	Input data hold time	All ⁽¹⁾⁽²⁾	12.5	−	ns
T _{QSPISSCLK2}	Slave select asserted to next clock edge	All ⁽¹⁾⁽²⁾	1	−	F _{QSPI_REF_CLK} cycle
T _{QSPICLKSS2}	Clock edge to slave select deasserted	All ⁽¹⁾⁽²⁾	1	−	F _{QSPI_REF_CLK} cycle
F _{QSPICLK2}	Quad-SPI device clock frequency	All ⁽¹⁾⁽²⁾	−	40	MHz
Feedback Clock Enabled or Disabled					
F _{QSPI_REF_CLK}	Quad-SPI reference clock frequency	All ⁽¹⁾⁽²⁾	−	200	MHz

Notes:

1. Test conditions: LVCMOS33, slow slew rate, 8 mA drive strength, 15 pF loads, feedback clock pin has no load. Quad-SPI single slave select 4-bit I/O mode.
2. Test conditions: LVCMOS33, slow slew rate, 8 mA drive strength, 30 pF loads in 4-bit stacked I/O configuration, feedback clock pin has no load. Quad-SPI single slave select 4-bit I/O mode.
3. The $T_{QSPICKO1}$ is an effective value. Use it to compute the available memory device input setup and hold timing budgets based on the given device clock-out duty-cycle limits.
4. Requires appropriate component selection/board design.

I2C Interfaces

Table 39: I2C Fast Mode Interface Switching Characteristics⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
$T_{DCI2CFCLK}$	I2C{0,1}SCL duty cycle	–	50	–	%
$T_{I2CFCKO}$	I2C{0,1}SDAO clock to out delay	–	–	900	ns
$T_{I2CFDCK}$	I2C{0,1}SDAI setup time	100	–	–	ns
$F_{I2CFCLK}$	I2C{0,1}SCL clock frequency	–	–	400	KHz

Notes:

- Test conditions: LVCMOS33, slow slew rate, 8 mA drive strength, 15 pF loads.

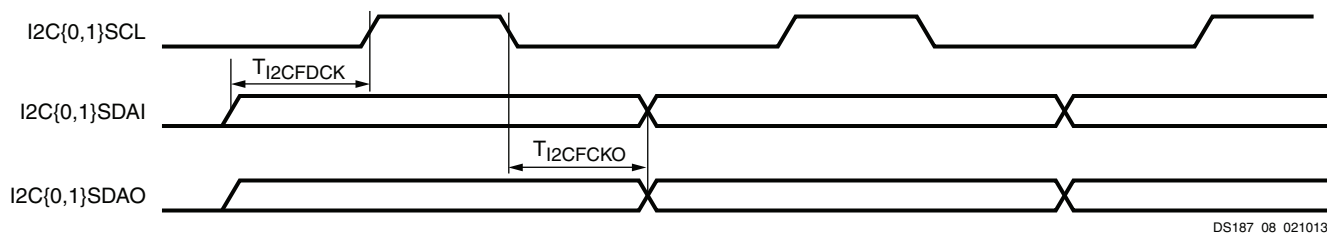


Figure 10: I2C Fast Mode Interface Timing Diagram

Table 40: I2C Standard Mode Interface Switching Characteristics⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
$T_{DCI2CSCLK}$	I2C{0,1}SCL duty cycle	–	50	–	%
$T_{I2CSCKO}$	I2C{0,1}SDAO clock to out delay	–	–	3450	ns
$T_{I2CSDCK}$	I2C{0,1}SDAI setup time	250	–	–	ns
$F_{I2CSCLK}$	I2C{0,1}SCL clock frequency	–	–	100	KHz

Notes:

- Test conditions: LVCMOS33, slow slew rate, 8 mA drive strength, 15 pF loads.

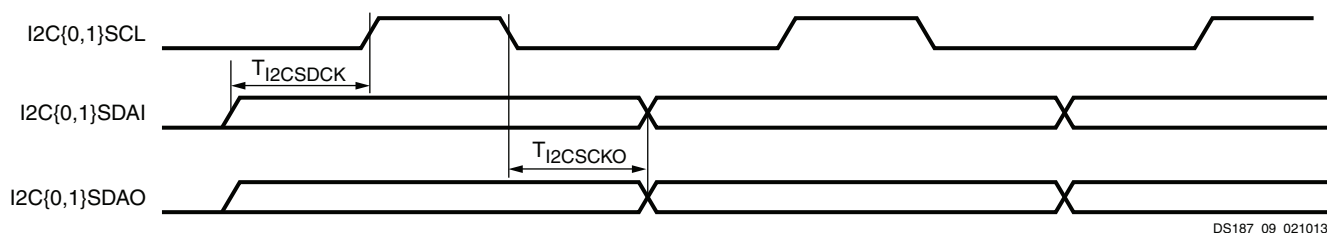


Figure 11: I2C Standard Mode Interface Timing Diagram

Table 52: IOB High Range (HR) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1C/-1I/-1LI	-1Q	-3	-2	-1C/-1I/-1LI	-1Q	-3	-2	-1C/-1I/-1LI	-1Q	
LVC MOS18_F24	0.74	0.83	0.89	0.97	1.34	1.46	1.71	2.28	1.35	1.49	1.73	2.29	ns
LVC MOS15_S4	0.77	0.86	0.93	0.96	2.05	2.18	2.43	2.43	2.07	2.21	2.45	2.45	ns
LVC MOS15_S8	0.77	0.86	0.93	0.96	2.09	2.21	2.46	2.46	2.10	2.24	2.48	2.48	ns
LVC MOS15_S12	0.77	0.86	0.93	0.96	1.59	1.71	1.96	1.96	1.60	1.74	1.98	1.98	ns
LVC MOS15_S16	0.77	0.86	0.93	0.96	1.59	1.71	1.96	1.96	1.60	1.74	1.98	1.98	ns
LVC MOS15_F4	0.77	0.86	0.93	0.96	1.85	1.97	2.23	2.23	1.87	2.00	2.24	2.24	ns
LVC MOS15_F8	0.77	0.86	0.93	0.96	1.60	1.72	1.98	1.98	1.62	1.75	1.99	1.99	ns
LVC MOS15_F12	0.77	0.86	0.93	0.96	1.35	1.47	1.73	1.73	1.37	1.50	1.74	1.74	ns
LVC MOS15_F16	0.77	0.86	0.93	0.96	1.34	1.46	1.71	2.07	1.35	1.49	1.73	2.09	ns
LVC MOS12_S4	0.87	0.95	1.02	1.19	2.57	2.69	2.95	2.95	2.59	2.72	2.96	2.96	ns
LVC MOS12_S8	0.87	0.95	1.02	1.19	2.09	2.21	2.46	2.46	2.10	2.24	2.48	2.48	ns
LVC MOS12_S12	0.87	0.95	1.02	1.19	1.79	1.91	2.17	2.17	1.81	1.94	2.18	2.18	ns
LVC MOS12_F4	0.87	0.95	1.02	1.19	1.98	2.10	2.35	2.35	1.99	2.13	2.37	2.37	ns
LVC MOS12_F8	0.87	0.95	1.02	1.19	1.54	1.66	1.92	1.92	1.56	1.69	1.93	1.93	ns
LVC MOS12_F12	0.87	0.95	1.02	1.19	1.38	1.51	1.76	1.76	1.40	1.54	1.77	1.77	ns
SSTL135_S	0.67	0.75	0.82	0.88	1.35	1.47	1.73	1.73	1.37	1.50	1.74	1.74	ns
SSTL15_S	0.60	0.68	0.75	0.75	1.30	1.43	1.68	1.71	1.32	1.46	1.69	1.73	ns
SSTL18_I_S	0.67	0.75	0.82	0.86	1.67	1.79	2.04	2.04	1.68	1.82	2.06	2.06	ns
SSTL18_II_S	0.67	0.75	0.82	0.88	1.31	1.43	1.68	1.68	1.32	1.46	1.70	1.70	ns
DIFF_SSTL135_S	0.68	0.76	0.83	0.88	1.35	1.47	1.73	1.73	1.37	1.50	1.74	1.74	ns
DIFF_SSTL15_S	0.68	0.76	0.83	0.88	1.30	1.43	1.68	1.71	1.32	1.46	1.69	1.73	ns
DIFF_SSTL18_I_S	0.71	0.79	0.86	0.88	1.68	1.80	2.06	2.06	1.70	1.83	2.07	2.07	ns
DIFF_SSTL18_II_S	0.71	0.79	0.86	0.88	1.38	1.51	1.76	1.76	1.40	1.54	1.77	1.77	ns
SSTL135_F	0.67	0.75	0.82	0.88	1.12	1.24	1.49	1.49	1.13	1.27	1.51	1.51	ns
SSTL15_F	0.60	0.68	0.75	0.75	1.07	1.19	1.45	1.45	1.09	1.22	1.46	1.46	ns
SSTL18_I_F	0.67	0.75	0.82	0.86	1.12	1.24	1.49	1.53	1.13	1.27	1.51	1.54	ns
SSTL18_II_F	0.67	0.75	0.82	0.88	1.12	1.24	1.49	1.51	1.13	1.27	1.51	1.52	ns
DIFF_SSTL135_F	0.68	0.76	0.83	0.88	1.12	1.24	1.49	1.49	1.13	1.27	1.51	1.51	ns
DIFF_SSTL15_F	0.68	0.76	0.83	0.88	1.07	1.19	1.45	1.45	1.09	1.22	1.46	1.46	ns
DIFF_SSTL18_I_F	0.71	0.79	0.86	0.88	1.23	1.35	1.60	1.60	1.24	1.38	1.62	1.62	ns
DIFF_SSTL18_II_F	0.71	0.79	0.86	0.88	1.21	1.33	1.59	1.59	1.23	1.36	1.60	1.60	ns

Table 53 specifies the values of T_{IOTPHZ} and $T_{IOBUFDISABLE}$. T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). $T_{IOBUFDISABLE}$ is described as the IOB delay from IBUFDISABLE to O output. In HR I/O banks, the internal IN_TERM termination turn-off time is always faster than T_{IOTPHZ} when the INTERMDISABLE pin is used.

Table 63: CLB Distributed RAM Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1C/-1I/-1LI	-1Q	
Setup and Hold Times Before/After Clock CLK						
T _{DS_LRAM} / T _{DH_LRAM}	A – D inputs to CLK	0.54/0.28	0.60/0.30	0.72/0.35	0.72/0.37	ns, Min
T _{AS_LRAM} / T _{AH_LRAM}	Address An inputs to clock	0.27/0.55	0.30/0.60	0.37/0.70	0.37/0.71	ns, Min
	Address An inputs through MUXs and/or carry logic to clock	0.69/0.18	0.77/0.21	0.94/0.26	0.94/0.35	ns, Min
T _{WS_LRAM} / T _{WH_LRAM}	WE input to clock	0.38/0.10	0.43/0.12	0.53/0.17	0.53/0.17	ns, Min
T _{CECK_LRAM} / T _{CKCE_LRAM}	CE input to CLK	0.39/0.10	0.44/0.11	0.53/0.17	0.53/0.17	ns, Min
Clock CLK						
T _{MPW_LRAM}	Minimum pulse width	1.05	1.13	1.25	1.25	ns, Min
T _{MCP}	Minimum clock period	2.10	2.26	2.50	2.50	ns, Min

Notes:

1. T_{SHCKO} also represents the CLK to XMUX output. Refer to the timing report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 64: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1C/-1I/-1LI	-1Q	
Sequential Delays						
T _{REG}	Clock to A – D outputs	1.19	1.33	1.61	1.61	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.58	1.77	2.15	2.15	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	1.12	1.23	1.46	1.46	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS_SHFREG} / T _{WH_SHFREG}	WE input	0.37/0.10	0.41/0.12	0.51/0.17	0.51/0.17	ns, Min
T _{CECK_SHFREG} / T _{CKCE_SHFREG}	CE input to CLK	0.37/0.10	0.42/0.11	0.52/0.17	0.52/0.17	ns, Min
T _{DS_SHFREG} / T _{DH_SHFREG}	A – D inputs to CLK	0.33/0.34	0.37/0.37	0.44/0.43	0.44/0.44	ns, Min
Clock CLK						
T _{MPW_SHFREG}	Minimum pulse width	0.77	0.86	0.98	0.98	ns, Min

DSP48E1 Switching Characteristics

Table 66: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1C/-1I/-1LI	-1Q	
Setup and Hold Times of Data/Control Pins to the Input Register Clock						
$T_{\text{DSPDCK_A_AREG}}/T_{\text{DSPCKD_A_AREG}}$	A input to A register CLK	0.26/0.12	0.30/0.13	0.37/0.14	0.37/0.28	ns
$T_{\text{DSPDCK_B_BREG}}/T_{\text{DSPCKD_B_BREG}}$	B input to B register CLK	0.33/0.15	0.38/0.16	0.45/0.18	0.45/0.25	ns
$T_{\text{DSPDCK_C_CREG}}/T_{\text{DSPCKD_C_CREG}}$	C input to C register CLK	0.17/0.17	0.20/0.19	0.24/0.21	0.24/0.26	ns
$T_{\text{DSPDCK_D_DREG}}/T_{\text{DSPCKD_D_DREG}}$	D input to D register CLK	0.25/0.25	0.32/0.27	0.42/0.27	0.42/0.42	ns
$T_{\text{DSPDCK_ACIN_AREG}}/T_{\text{DSPCKD_ACIN_AREG}}$	ACIN input to A register CLK	0.23/0.12	0.27/0.13	0.32/0.14	0.32/0.17	ns
$T_{\text{DSPDCK_BCIN_BREG}}/T_{\text{DSPCKD_BCIN_BREG}}$	BCIN input to B register CLK	0.25/0.15	0.29/0.16	0.36/0.18	0.36/0.18	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock						
$T_{\text{DSPDCK_}\{A, B\}_MREG_MULT}/T_{\text{DSPCKD_}\{A, B\}_MREG_MULT}$	{A, B} input to M register CLK using multiplier	2.40/−0.01	2.76/−0.01	3.29/−0.01	3.29/−0.01	ns
$T_{\text{DSPDCK_}\{A, D\}_ADREG}/T_{\text{DSPCKD_}\{A, D\}_ADREG}$	{A, D} input to AD register CLK	1.29/−0.02	1.48/−0.02	1.76/−0.02	1.76/−0.02	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock						
$T_{\text{DSPDCK_}\{A, B\}_PREG_MULT}/T_{\text{DSPCKD_}\{A, B\}_PREG_MULT}$	{A, B} input to P register CLK using multiplier	4.02/−0.28	4.60/−0.28	5.48/−0.28	5.48/−0.28	ns
$T_{\text{DSPDCK_D_PREG_MULT}}/T_{\text{DSPCKD_D_PREG_MULT}}$	D input to P register CLK using multiplier	3.93/−0.73	4.50/−0.73	5.35/−0.73	5.35/−0.73	ns
$T_{\text{DSPDCK_}\{A, B\}_PREG}/T_{\text{DSPCKD_}\{A, B\}_PREG}$	A or B input to P register CLK not using multiplier	1.73/−0.28	1.98/−0.28	2.35/−0.28	2.35/−0.28	ns
$T_{\text{DSPDCK_C_PREG}}/T_{\text{DSPCKD_C_PREG}}$	C input to P register CLK not using multiplier	1.54/−0.26	1.76/−0.26	2.10/−0.26	2.10/−0.26	ns
$T_{\text{DSPDCK_PCIN_PREG}}/T_{\text{DSPCKD_PCIN_PREG}}$	PCIN input to P register CLK	1.32/−0.15	1.51/−0.15	1.80/−0.15	1.80/−0.15	ns
Setup and Hold Times of the CE Pins						
$T_{\text{DSPDCK_}\{CEA;CEB\}_AREG;BREG}/T_{\text{DSPCKD_}\{CEA;CEB\}_AREG;BREG}$	{CEA; CEB} input to {A; B} register CLK	0.35/0.06	0.42/0.08	0.52/0.11	0.52/0.11	ns
$T_{\text{DSPDCK_CEC_CREG}}/T_{\text{DSPCKD_CEC_CREG}}$	CEC input to C register CLK	0.28/0.10	0.34/0.11	0.42/0.13	0.42/0.13	ns
$T_{\text{DSPDCK_CED_DREG}}/T_{\text{DSPCKD_CED_DREG}}$	CED input to D register CLK	0.36/−0.03	0.43/−0.03	0.52/−0.03	0.52/−0.03	ns
$T_{\text{DSPDCK_CEM_MREG}}/T_{\text{DSPCKD_CEM_MREG}}$	CEM input to M register CLK	0.17/0.18	0.21/0.20	0.27/0.23	0.27/0.23	ns
$T_{\text{DSPDCK_CEP_PREG}}/T_{\text{DSPCKD_CEP_PREG}}$	CEP input to P register CLK	0.36/0.01	0.43/0.01	0.53/0.01	0.53/0.01	ns
Setup and Hold Times of the RST Pins						
$T_{\text{DSPDCK_}\{RSTA;RSTB\}_AREG;BREG}/T_{\text{DSPCKD_}\{RSTA;RSTB\}_AREG;BREG}$	{RSTA, RSTB} input to {A, B} register CLK	0.41/0.11	0.46/0.13	0.55/0.15	0.55/0.24	ns
$T_{\text{DSPDCK_RSTC_CREG}}/T_{\text{DSPCKD_RSTC_CREG}}$	RSTC input to C register CLK	0.07/0.10	0.08/0.11	0.09/0.12	0.09/0.25	ns
$T_{\text{DSPDCK_RSTD_DREG}}/T_{\text{DSPCKD_RSTD_DREG}}$	RSTD input to D register CLK	0.44/0.07	0.50/0.08	0.59/0.09	0.59/0.09	ns
$T_{\text{DSPDCK_RSTM_MREG}}/T_{\text{DSPCKD_RSTM_MREG}}$	RSTM input to M register CLK	0.21/0.22	0.23/0.24	0.27/0.28	0.27/0.28	ns

Table 66: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1C/-1I/-1LI	-1Q	
Clock to Outs from Input Register Clock to Output Pins						
T _{DSPCKO_P_AREG_MULT}	CLK AREG to P output using multiplier	3.94	4.51	5.37	5.37	ns
T _{DSPCKO_P_BREG}	CLK BREG to P output not using multiplier	1.64	1.87	2.22	2.22	ns
T _{DSPCKO_P_CREG}	CLK CREG to P output not using multiplier	1.69	1.93	2.30	2.30	ns
T _{DSPCKO_P_DREG_MULT}	CLK DREG to P output using multiplier	3.91	4.48	5.32	5.32	ns
Clock to Outs from Input Register Clock to Cascading Output Pins						
T _{DSPCKO_{ACOUT; BCOUT}_{AREG; BREG}}	CLK (ACOUT, BCOUT) to {A,B} register output	0.64	0.73	0.87	0.87	ns
T _{DSPCKO_CARRYCASCOUT_{AREG, BREG}_MULT}	CLK (AREG, BREG) to CARRYCASCOUT output using multiplier	4.19	4.79	5.70	5.70	ns
T _{DSPCKO_CARRYCASCOUT_BREG}	CLK BREG to CARRYCASCOUT output not using multiplier	1.88	2.15	2.55	2.55	ns
T _{DSPCKO_CARRYCASCOUT_DREG_MULT}	CLK DREG to CARRYCASCOUT output using multiplier	4.16	4.76	5.65	5.65	ns
T _{DSPCKO_CARRYCASCOUT_CREG}	CLK CREG to CARRYCASCOUT output	1.94	2.21	2.63	2.63	ns
Maximum Frequency						
F _{MAX}	With all registers used	628.93	550.66	464.25	464.25	MHz
F _{MAX_PATDET}	With pattern detector	531.63	465.77	392.93	392.93	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG	349.28	305.62	257.47	257.47	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect	317.26	277.62	233.92	233.92	MHz
F _{MAX_PREADD_MULT_NOADREG}	Without ADREG	397.30	346.26	290.44	290.44	MHz
F _{MAX_PREADD_MULT_NOADREG_PATDET}	Without ADREG with pattern detect	397.30	346.26	290.44	290.44	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG)	260.01	227.01	190.69	190.69	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect	241.72	211.15	177.43	177.43	MHz

Table 72: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1C/-1I/-1LI	-1Q	
MMCM_T _{LOCKMAX}	MMCM maximum lock time	100.00	100.00	100.00	100.00	μs
MMCM_F _{OUTMAX}	MMCM maximum output frequency	800.00	800.00	800.00	800.00	MHz
MMCM_F _{OUTMIN}	MMCM minimum output frequency ⁽⁵⁾⁽⁶⁾	4.69	4.69	4.69	4.69	MHz
MMCM_T _{EXTFDVAR}	External clock feedback variation	< 20% of clock input period or 1 ns Max				
MMCM_RST _{MINPULSE}	Minimum reset pulse width	5.00	5.00	5.00	5.00	ns
MMCM_F _{PFDMAX}	Maximum frequency at the phase frequency detector	550.00	500.00	450.00	450.00	MHz
MMCM_F _{PFDMIN}	Minimum frequency at the phase frequency detector	10.00	10.00	10.00	10.00	MHz
MMCM_T _{FBDELAY}	Maximum delay in the feedback path	3 ns Max or one CLKIN cycle				
MMCM Switching Characteristics Setup and Hold						
T _{MMCMDCK_PSEN} / T _{MMCMCKD_PSEN}	Setup and hold of phase-shift enable	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
T _{MMCMDCK_PSINCDEC} / T _{MMCMCKD_PSINCDEC}	Setup and hold of phase-shift increment/decrement	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
T _{MMCMCKO_PSDONE}	Phase shift clock-to-out of PSDONE	0.59	0.68	0.81	0.81	ns
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
T _{MMCMDCK_DADDR} / T _{MMCMCKD_DADDR}	DADDR setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.63/0.15	ns, Min
T _{MMCMDCK_DI} / T _{MMCMCKD_DI}	DI setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.63/0.15	ns, Min
T _{MMCMDCK_DEN} / T _{MMCMCKD_DEN}	DEN setup/hold	1.76/0.00	1.97/0.00	2.29/0.00	2.29/0.00	ns, Min
T _{MMCMDCK_DWE} / T _{MMCMCKD_DWE}	DWE setup/hold	1.25/0.15	1.40/0.15	1.63/0.15	1.63/0.15	ns, Min
T _{MMCMCKO_DRDY}	CLK to out of DRDY	0.65	0.72	0.99	0.99	ns, Max
F _{DCK}	DCLK frequency	200.00	200.00	200.00	200.00	MHz, Max

Notes:

1. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any MMCM outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as F_{VCO}/128 assuming output duty cycle is 50%.
6. When CLKOUT4_CASCADE = TRUE, MMCM_F_{OUTMIN} is 0.036 MHz.

Device Pin-to-Pin Input Parameter Guidelines

Table 79: Global Clock Input Setup and Hold Without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1C/-1I/-1LI	-1Q	
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾							
T _{PSFD} / T _{PHFD}	Full delay (legacy delay or default delay) global clock input and IFF ⁽²⁾ without MMCM/PLL with ZHOLD_DELAY on HR I/O banks	XC7Z007S	N/A	2.13/−0.17	2.44/−0.17	N/A	ns
		XC7Z012S	N/A	2.55/−0.18	3.03/−0.18	N/A	ns
		XC7Z014S	N/A	2.74/−0.25	3.18/−0.25	N/A	ns
		XC7Z010	2.00/−0.17	2.13/−0.17	2.44/−0.17	N/A	ns
		XC7Z015	2.38/−0.18	2.55/−0.18	3.03/−0.18	N/A	ns
		XC7Z020	2.55/−0.25	2.74/−0.25	3.18/−0.25	N/A	ns
		XA7Z010	N/A	N/A	2.44/−0.17	2.44/−0.17	ns
		XA7Z020	N/A	N/A	3.18/−0.25	3.18/−0.25	ns
		XQ7Z020	N/A	2.74/−0.25	3.18/−0.25	3.18/−0.25	ns

Notes:

- Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input flip-flop or latch.

Table 80: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1C/-1I/-1LI	-1Q	
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. ⁽¹⁾							
T _{PSMMCMCC} / T _{PHMMCMCC}	No delay clock-capable clock input and IFF ⁽²⁾ with MMCM	XC7Z007S	N/A	2.68/−0.62	3.22/−0.62	N/A	ns
		XC7Z012S	N/A	2.80/−0.62	3.34/−0.62	N/A	ns
		XC7Z014S	N/A	2.82/−0.62	3.38/−0.62	N/A	ns
		XC7Z010	2.36/−0.62	2.68/−0.62	3.22/−0.62	N/A	ns
		XC7Z015	2.47/−0.62	2.80/−0.62	3.34/−0.62	N/A	ns
		XC7Z020	2.48/−0.62	2.82/−0.62	3.38/−0.62	N/A	ns
		XA7Z010	N/A	N/A	3.22/−0.62	3.22/−0.62	ns
		XA7Z020	N/A	N/A	3.38/−0.62	3.38/−0.62	ns
		XQ7Z020	N/A	2.82/−0.62	3.38/−0.62	3.38/−0.62	ns

Notes:

- Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input flip-flop or latch
- Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 81: Clock-Capable Clock Input Setup and Hold With PLL

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1C/-1I/-1LI	-1Q	
Input Setup and Hold Time Relative to Clock-Capable Clock Input Signal for SSTL15 Standard. ⁽¹⁾							
T _{PSPLLCC} / T _{PHPLLCC}	No delay clock-capable clock input and IFF ⁽²⁾ with PLL	XC7Z007S	N/A	3.03/−0.19	3.64/−0.19	N/A	ns
		XC7Z012S	N/A	3.15/−0.20	3.76/−0.20	N/A	ns
		XC7Z014S	N/A	3.17/−0.20	3.80/−0.20	N/A	ns
		XC7Z010	2.67/−0.19	3.03/−0.19	3.64/−0.19	N/A	ns
		XC7Z015	2.78/−0.20	3.15/−0.20	3.76/−0.20	N/A	ns
		XC7Z020	2.79/−0.20	3.17/−0.20	3.80/−0.20	N/A	ns
		XA7Z010	N/A	N/A	3.64/−0.19	3.64/−0.19	ns
		XA7Z020	N/A	N/A	3.80/−0.20	3.80/−0.20	ns
		XQ7Z020	N/A	3.17/−0.20	3.80/−0.20	3.80/−0.20	ns

Notes:

- Setup and hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the global clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the global clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input flip-flop or latch
- Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 82: Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO

Symbol	Description	Speed Grade				Units
		-3	-2	-1C/-1I/-1LI	-1Q	
Input Setup and Hold Time Relative to a Forwarded Clock Input Pin Using BUFIO for SSTL15 Standard.						
T _{PSCS} /T _{PHCS}	Setup and hold of I/O clock	−0.38/1.39	−0.38/1.55	−0.38/1.86	−0.38/1.86	ns

Table 83: Sample Window

Symbol	Description	Speed Grade				Units
		-3	-2	-1C/-1I/-1LI	-1Q	
T _{SAMP}	Sampling error at receiver pins ⁽¹⁾	0.59	0.64	0.70	0.70	ns
T _{SAMP_BUFIO}	Sampling error at receiver pins using BUFIO ⁽²⁾	0.35	0.40	0.46	0.46	ns

Notes:

- This parameter indicates the total sampling error of the PL DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
These measurements do not include package or clock tree skew.
- This parameter indicates the total sampling error of the PL DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IDELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Additional Package Parameter Guidelines

The parameters in this section provide the necessary values for calculating timing budgets for PL clock transmitter and receiver data-valid windows.

Table 84: Package Skew

Symbol	Description	Device	Package	Value	Units
T _{PKGSKEW}	Package skew ⁽¹⁾	XC7Z007S	CLG225	101	ps
			CLG400	155	ps
		XC7Z012S	CLG485	182	ps
		XC7Z014S	CLG400	166	ps
			CLG484	248	ps
		XC7Z010	CLG225	101	ps
			CLG400	155	ps
		XC7Z015	CLG485	182	ps
		XC7Z020	CLG400	166	ps
			CLG484	248	ps
		XA7Z010	CLG225	101	ps
			CLG400	155	ps
		XA7Z020	CLG400	166	ps
			CLG484	248	ps
		XQ7Z020	CL400	166	ps
			CL484	248	ps

Notes:

- These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from die pad to ball.
- Package delay information is available for these device/package combinations. This information can be used to deskew the package.

GTP Transceiver Specifications (Only available in the XC7Z012S and XC7Z015)

GTP Transceiver DC Input and Output Levels

Table 85 summarizes the DC output specifications of the GTP transceivers in the XC7Z012S and XC7Z015. Consult the *7 Series FPGAs GTP Transceiver User Guide* (UG482) for further details.

Table 85: GTP Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV _{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	1000	–	–	mV
V _{CMOUTDC}	DC common mode output voltage	Equation based	$V_{MGTAVTT} - DV_{PPOUT}/4$			mV
R _{OUT}	Differential output resistance		–	100	–	Ω
V _{CMOUTAC}	Common mode output voltage: AC coupled		$1/2 V_{MGTAVTT}$			mV
T _{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	–	12	ps
DV _{PPIN}	Differential peak-to-peak input voltage	External AC coupled	150	–	2000	mV
V _{IN}	Single-ended input voltage ⁽²⁾	DC coupled $V_{MGTAVTT} = 1.2V$	–200	–	$V_{MGTAVTT}$	mV
V _{CMIN}	Common mode input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	–	$2/3 V_{MGTAVTT}$	–	mV
R _{IN}	Differential input resistance		–	100	–	Ω
C _{EXT}	Recommended external AC coupling capacitor ⁽³⁾		–	100	–	nF

Notes:

1. The output swing and preemphasis levels are programmable using the attributes discussed in the *7 Series FPGAs GTP Transceiver User Guide* (UG482) and can result in values lower than reported in this table.
2. Voltage measured at the pin referenced to GND.
3. Other values can be used as appropriate to conform to specific protocols and standards.

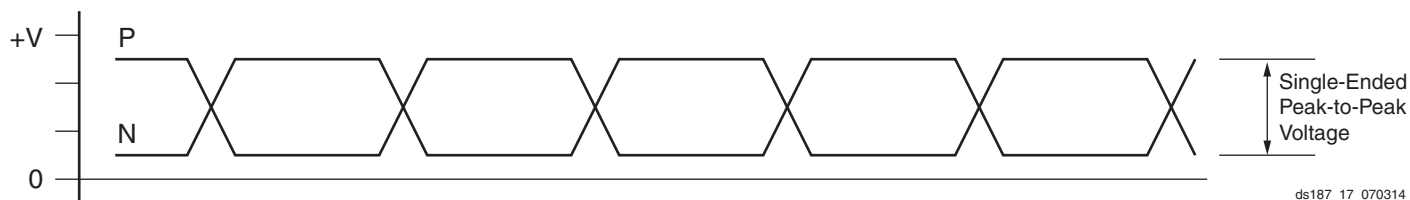


Figure 20: Single-Ended Peak-to-Peak Voltage

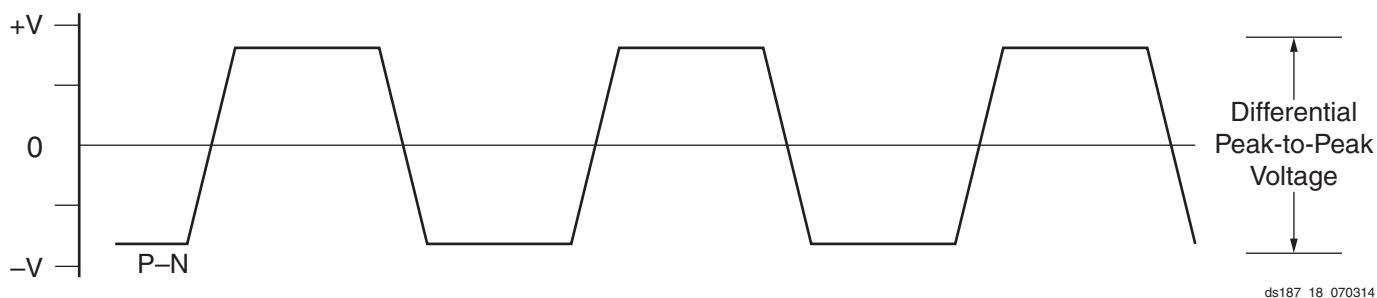


Figure 21: Differential Peak-to-Peak Voltage

Note: In Figure 21, differential peak-to-peak voltage = single-ended peak-to-peak voltage x 2.

Table 86 summarizes the DC specifications of the clock input of the GTP transceiver. Consult the *7 Series FPGAs GTP Transceiver User Guide* (UG482) for further details.

Table 86: GTP Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	350	–	2000	mV
R_{IN}	Differential input resistance	–	100	–	Ω
C_{EXT}	Required external AC coupling capacitor	–	100	–	nF

GTP Transceiver Switching Characteristics

Consult the *7 Series FPGAs GTP Transceiver User Guide* (UG482) for further information.

Table 87: GTP Transceiver Performance

Symbol	Description	Output Divider	Speed Grade				Units
			-3	-2	-1C/-1I/-1LI	-1Q	
F_{GTPMAX}	Maximum GTP transceiver data rate		6.25	6.25	3.75	N/A	Gb/s
F_{GTPMIN}	Minimum GTP transceiver data rate		0.500	0.500	0.500	N/A	Gb/s
$F_{GTPRANGE}$	PLL line rate range	1	3.2–6.25	3.2–6.25	3.2–3.75	N/A	Gb/s
		2	1.6–3.3	1.6–3.3	1.6–3.2	N/A	Gb/s
		4	0.8–1.65	0.8–1.65	0.8–1.6	N/A	Gb/s
		8	0.5–0.825	0.5–0.825	0.5–0.8	N/A	Gb/s
F_{GTPPLL}	GTP transceiver PLL frequency range		1.6–3.3	1.6–3.3	1.6–3.3	N/A	GHz

Table 88: GTP Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1C/-1I/-1LI	-1Q	
$F_{GTPDRPCLK}$	GTPDRPCLK maximum frequency	175	175	156	N/A	MHz

Table 89: GTP Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range		60	–	660	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	–	60	%

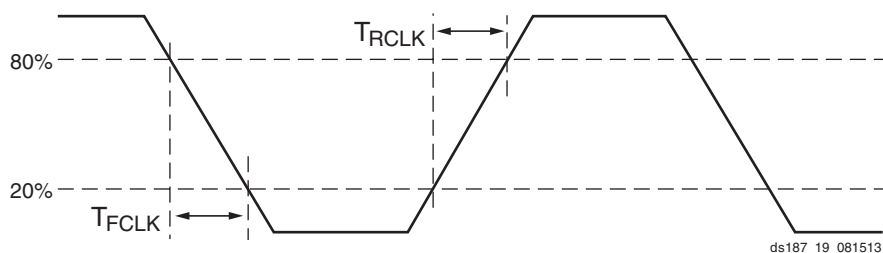


Figure 22: Reference Clock Timing Parameters

Table 93: GTP Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F _{GTPRX}	Serial data rate	RX oversampler not enabled	0.500	–	F _{GTPMAX}	Gb/s
T _{RXELECIDLE}	Time for RXELECIDLE to respond to loss or restoration of data		–	10	–	ns
RX _{OOBVDP}	OOB detect threshold peak-to-peak		60	–	150	mV
RX _{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	–5000	–	5000	ppm
RX _{RL}	Run length (CID)		–	–	512	UI
RX _{PPMTOL}	Data/REFCLK PPM offset tolerance		–1250	–	1250	ppm
SJ Jitter Tolerance ⁽²⁾						
JT_SJ _{6.25}	Sinusoidal Jitter ⁽³⁾	6.25 Gb/s	0.44	–	–	UI
JT_SJ _{5.0}	Sinusoidal Jitter ⁽³⁾	5.0 Gb/s	0.44	–	–	UI
JT_SJ _{4.25}	Sinusoidal Jitter ⁽³⁾	4.25 Gb/s	0.44	–	–	UI
JT_SJ _{3.75}	Sinusoidal Jitter ⁽³⁾	3.75 Gb/s	0.44	–	–	UI
JT_SJ _{3.2}	Sinusoidal Jitter ⁽³⁾	3.2 Gb/s ⁽⁴⁾	0.45	–	–	UI
JT_SJ _{3.2L}	Sinusoidal Jitter ⁽³⁾	3.2 Gb/s ⁽⁵⁾	0.45	–	–	UI
JT_SJ _{2.5}	Sinusoidal Jitter ⁽³⁾	2.5 Gb/s ⁽⁶⁾	0.5	–	–	UI
JT_SJ _{1.25}	Sinusoidal Jitter ⁽³⁾	1.25 Gb/s ⁽⁷⁾	0.5	–	–	UI
JT_SJ ₅₀₀	Sinusoidal Jitter ⁽³⁾	500 Mb/s	0.4	–	–	UI
SJ Jitter Tolerance with Stressed Eye ⁽²⁾						
JT_TJSE _{3.2}	Total Jitter with Stressed Eye ⁽⁸⁾	3.2 Gb/s	0.70	–	–	UI
JT_TJSE _{6.25}		6.25 Gb/s	0.70	–	–	UI
JT_SJSE _{3.2}	Sinusoidal Jitter with Stressed Eye ⁽⁸⁾	3.2 Gb/s	0.1	–	–	UI
JT_SJSE _{6.25}		6.25 Gb/s	0.1	–	–	UI

Notes:

- Using $RXOUT_DIV = 1, 2, \text{ and } 4$.
- All jitter values are based on a bit error ratio of $1e^{-12}$.
- The frequency of the injected sinusoidal jitter is 10 MHz.
- PLL frequency at 3.2 GHz and $RXOUT_DIV = 2$.
- PLL frequency at 1.6 GHz and $RXOUT_DIV = 1$.
- PLL frequency at 2.5 GHz and $RXOUT_DIV = 2$.
- PLL frequency at 2.5 GHz and $RXOUT_DIV = 4$.
- Composite jitter.